Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.			SERIAL NO.			
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18,	AO	WO 99/61141	12/02/1999	WIPO						
le	AP.	WO 99/38897	08/05/1999		WIPO (with English Abstract, corr. US 6,670,424 was cited on 08/12/04)					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)										
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	AZ				Additional References sheet(s) attached					
Examiner	Examiner \\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\					Date Considered 20 December 2004				
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										